Semiconductor devices - Mechanical and climatic test methods - Part 26: Electrostatic discharge (ESD) sensitivity testing - Human body model (HBM)

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NATIONAL FOREWORD

See Eesti standard EVS-EN 60749-26:2014 sisaldab Euroopa standardi EN 60749-26:2014 inglisekeelset teksti.	This Estonian standard EVS-EN 60749-26:2014 consists of the English text of the European standard EN 60749-26:2014.
Standard on jõustunud sellekohase teate avaldamisega EVS Teatajas.	This standard has been endorsed with a notification published in the official bulletin of the Estonian Centre for Standardisation.
Euroopa standardimisorganisatsioonid on teinud Euroopa standardi rahvuslikele liikmetele kättesaadavaks 23.05.2014.	Date of Availability of the European standard is 23.05.2014.
Standard on kättesaadav Eesti Standardikeskusest.	The standard is available from the Estonian Centre for Standardisation.

Tagasisidet standardi sisu kohta on võimalik edastada, kasutades EVS-i veebilehel asuvat tagasiside vormi või saates e-kirja meiliaadressile standardiosakond@evs.ee.

ICS 31.080.01

EUROPEAN STANDARD

NORME EUROPÉENNE

EUROPÄISCHE NORM

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Supersedes EN 60749-26:2006

English Version

Semiconductor devices - Mechanical and climatic test methods - Part 26: Electrostatic discharge (ESD) sensitivity testing - Human body model (HBM) (IEC 60749-26:2013)

Dispositifs à semiconducteurs - Méthodes d'essais mécaniques et climatiques - Partie 26: Essai de sensibilité aux décharges électrostatiques (DES) - Modèle du corps humain (HBM)
(CEI 60749-26:2013)

Halbleiterbauelemente - Mechanische und klimatische Prüfverfahren - Teil 26: Prüfung der Empfindlichkeit gegen elektrostatische Entladungen (ESD) - Human Body Model (HBM)
(IEC 60749-26:2013)

This European Standard was approved by CENELEC on 2014-04-14. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the CEN-CENELEC Management Centre or to any CENELEC member.

This European Standard exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the CEN-CENELEC Management Centre has the same status as the official versions.

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European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

CEN-CENELEC Management Centre: Avenue Marnix 17, B-1000 Brussels

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Foreword

This document (EN 60749-26:2014) consists of the text of IEC 60749-26:2013 prepared by IEC/TC 47 "Semiconductor devices", in collaboration with Technical Committee 101.

The following dates are fixed:

• latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement	(dop)	2015-04-14
• latest date by which the national standards conflicting with the document have to be withdrawn	(dow)	2017-04-14

This document supersedes EN 60749-26:2006.

EN 60749-26:2014 includes the following significant technical changes with respect to EN 60749-26:2006:

a) descriptions of oscilloscope and current transducers have been refined and updated;

b) the HBM circuit schematic and description have been improved;

c) the description of stress test equipment qualification and verification has been completely re-written;

d) qualification and verification of test fixture boards has been revised;

e) a new section on the determination of ringing in the current waveform has been added;

f) some alternate pin combinations have been included;

g) allowance for non-supply pins to stress to a limited number of supply pin groups (associated non-supply pins) and allowance for non-supply to non-supply (i.e., I/O to I/O) stress to be limited to a finite number of 2 pin pairs (coupled non-supply pin pairs);

h) explicit allowance for HBM stress using 2 pin HBM testers for die only shorted supply groups.

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. CENELEC [and/or CEN] shall not be held responsible for identifying any or all such patent rights.

Endorsement notice

The text of the International Standard IEC 60749-26:2013 was approved by CENELEC as a European Standard without any modification.

Annex ZA
(normative)

Normative references to international publications with their corresponding European publications

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 When an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu

Publication	Year	Title	EN/HD	Year
IEC 60749-27	-	Semiconductor devices - Mechanical and climatic test methods - Part 27: Electrostatic discharge (ESD) sensitivity testing - Machine model (MM)	EN 60749-27	-

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